

Automotive Chip Choke®

EMI Suppression for CAN-Bus Networks

2-Line Common Mode Chokes



- Meets AEC-Q200 Requirements
- Suppression of common mode noise without attenuating the signal
- Magnetically shielded versions for lower Rdc and higher current
- Supports CAN-Bus, A2B and other IVN high speed differential signal lines (LVDS)

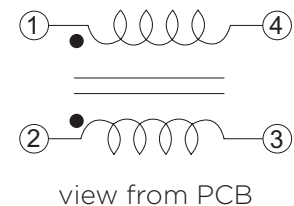
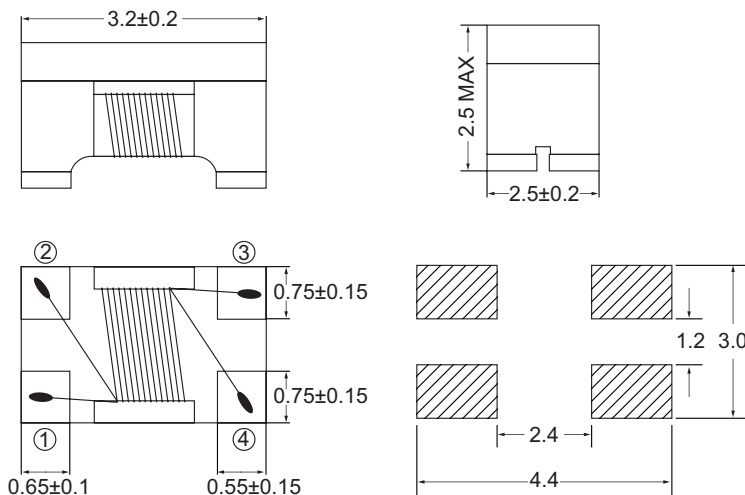
Electrical Specifications @ 25°C - Operating Temperature -40°C to +125°C

Part Number	Common Mode Impedance (10MHZ)		Inductance (uH)	Standard Tolerance	RDC (Ω Max)	IDC (A MAX)	Isolation Resistance (MΩ) Min	Rated Voltage (V) Max
	Min	Typ						
PE-1210ACCXXXSTS								
PE-1210ACC110STS	300	550	11	+50/-30%	0.4	0.3	10	80
PE-1210ACC220STS	500	1100	22	+50/-30%	0.5	0.25	10	80
PE-1210ACC510STS	1000	2600	51	+50/-30%	0.7	0.2	10	80
PE-1210ACC101STS	2200	5100	100	+50/-30%	1.5	0.15	10	80
PE-1812ACCXXXSTS								
PE-1812ACC110STS	300	600	11	+50/-30%	0.5	0.36	10	50
PE-1812ACC220STS	600	1200	22	+50/-30%	0.6	0.31	10	50
PE-1812ACC510STS	1500	3500	51	+50/-30%	1	0.23	10	50
PE-1812ACC101STS	3000	7500	100	+50/-30%	2	0.2	10	50

Mechanical

Schematic

PE-1210ACCXXXSTS



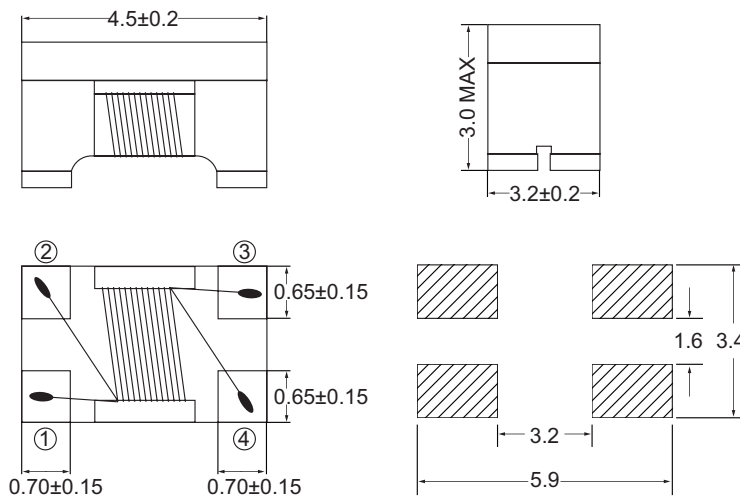
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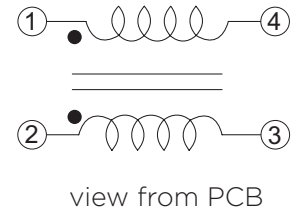
2-Line Common Mode Chokes

Mechanical

PE-1812ACCXXXSTS

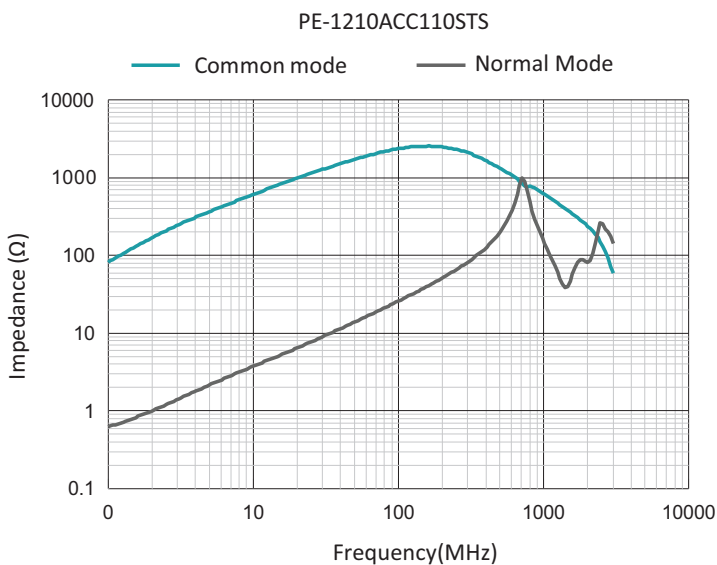


Schematic

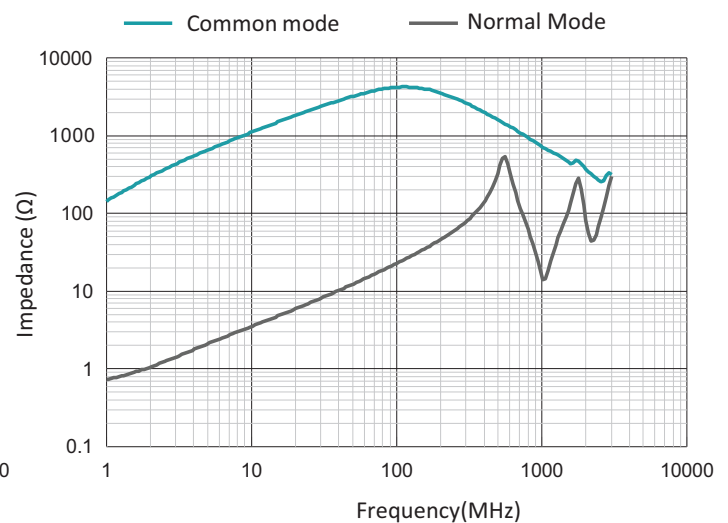


Impedance Curve

PE-1210ACCXXXSTS



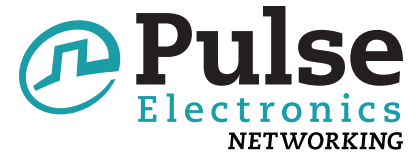
PE-1210ACC220STS



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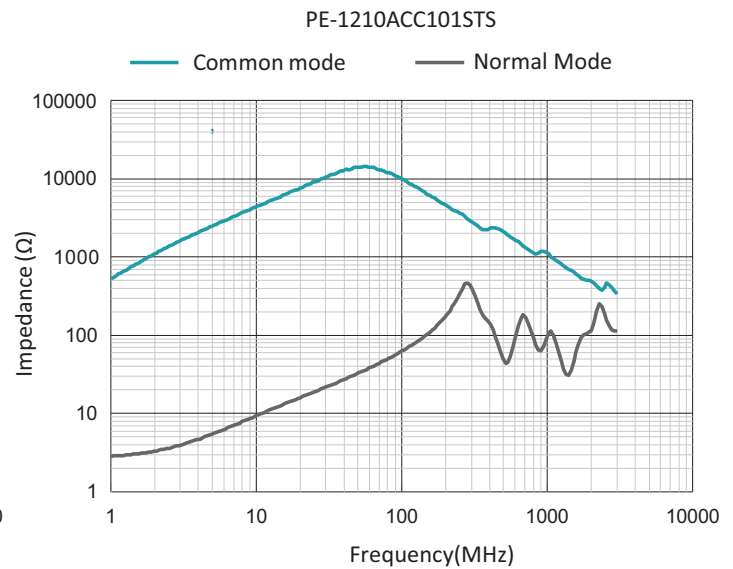
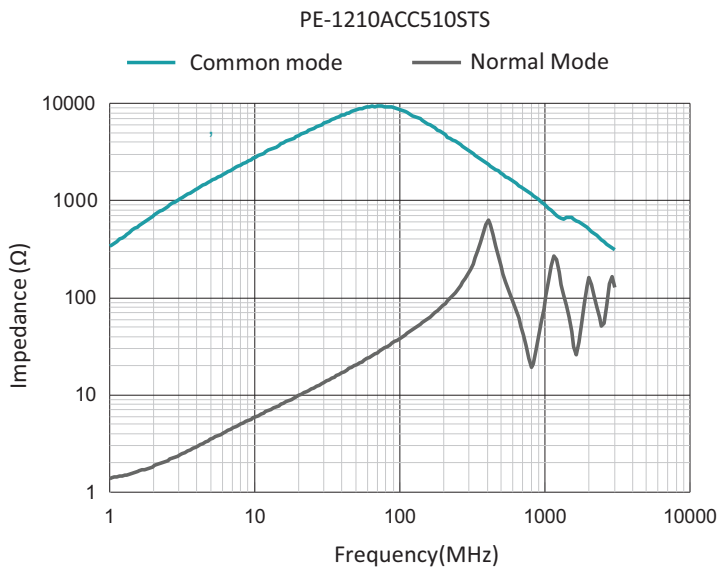
EMI Suppression for CAN-Bus Networks

2-Line Common Mode Chokes



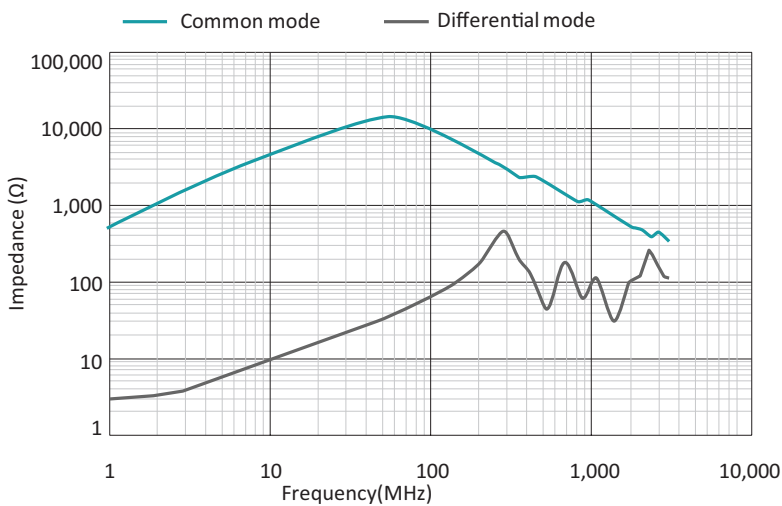
Impedance Curve

PE-1210ACCXXXSTS

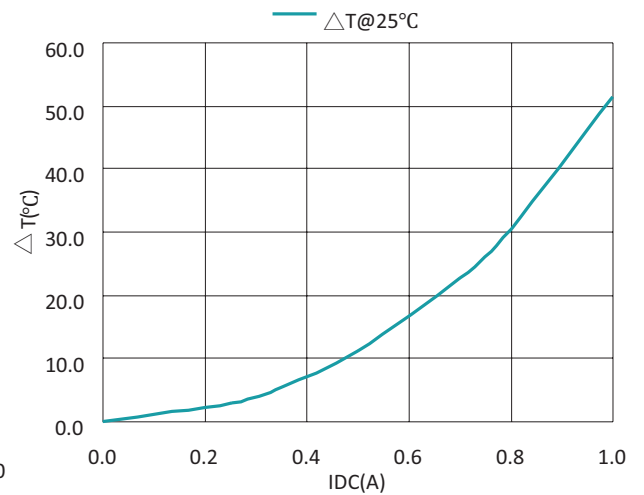


Impedance vs Frequency

PE-1210ACC101STS



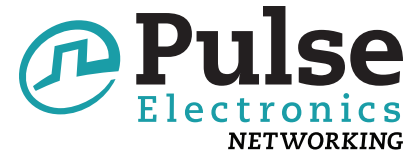
Temp vs DC Current



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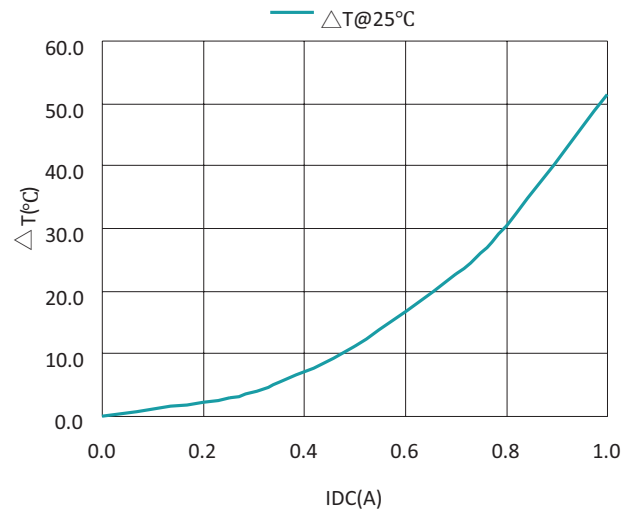
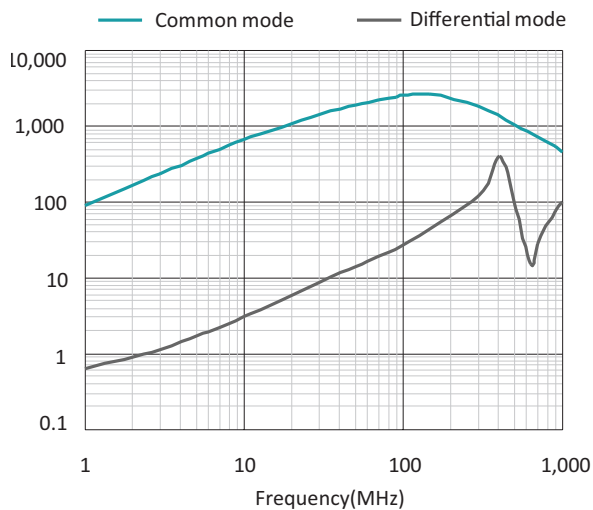
2-Line Common Mode Chokes



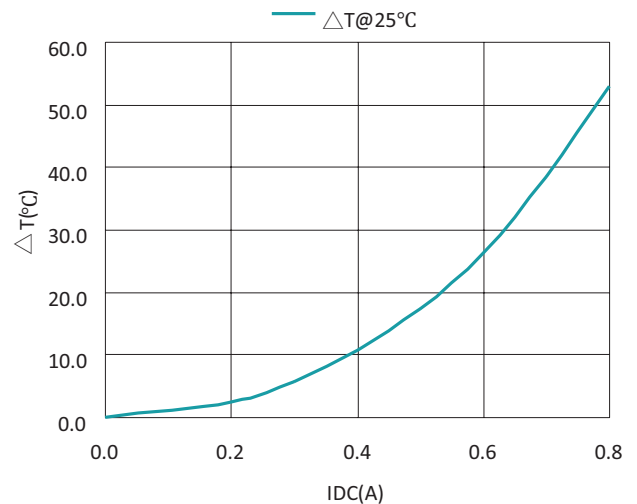
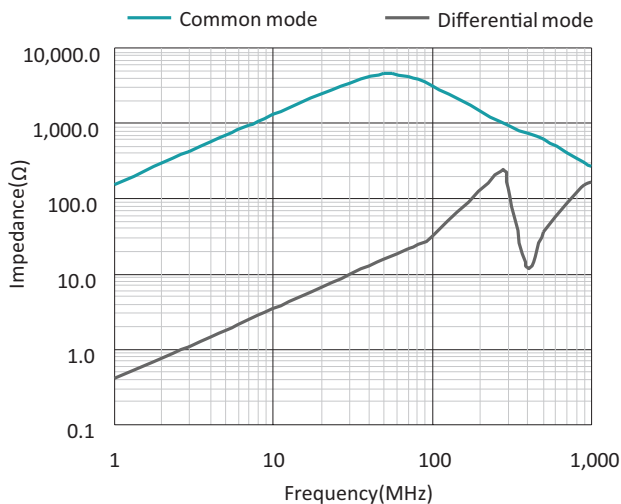
Impedance vs Frequency

Temp vs DC Current

PE-1812ACC110STS



PE-1812ACC220STS



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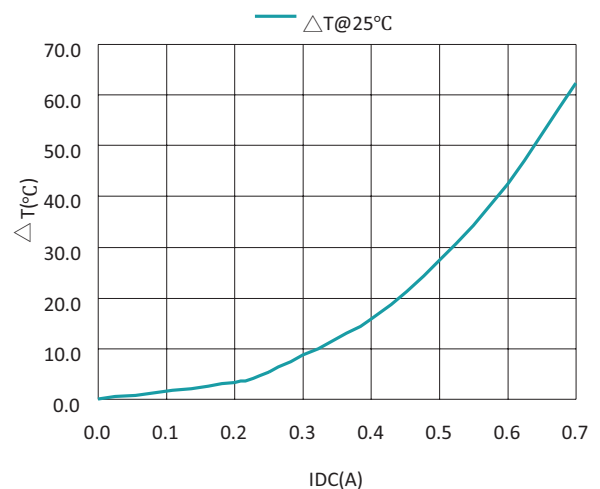
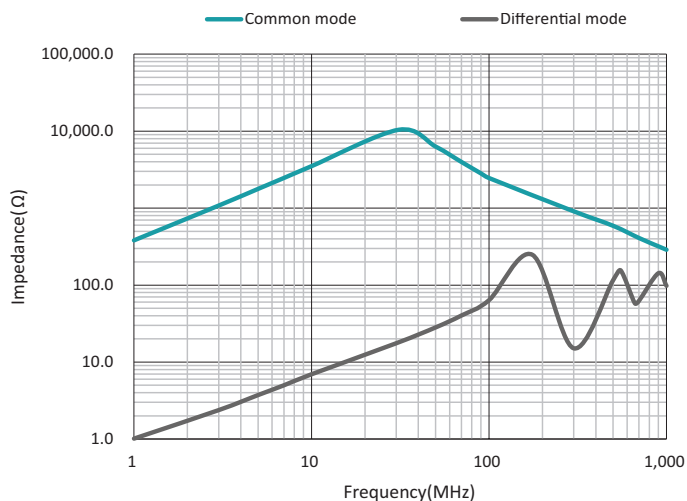
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2-Line Common Mode Chokes

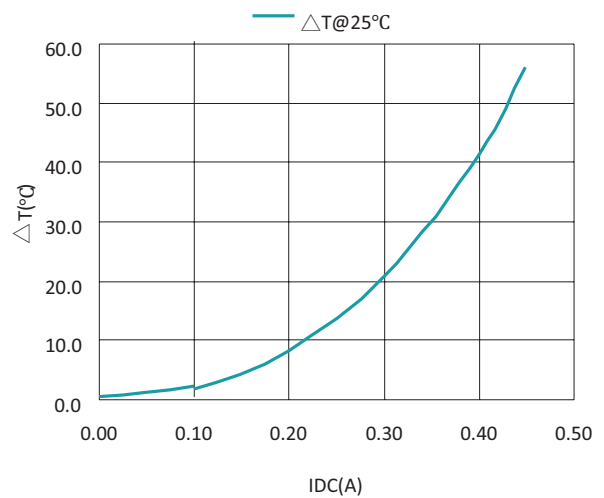
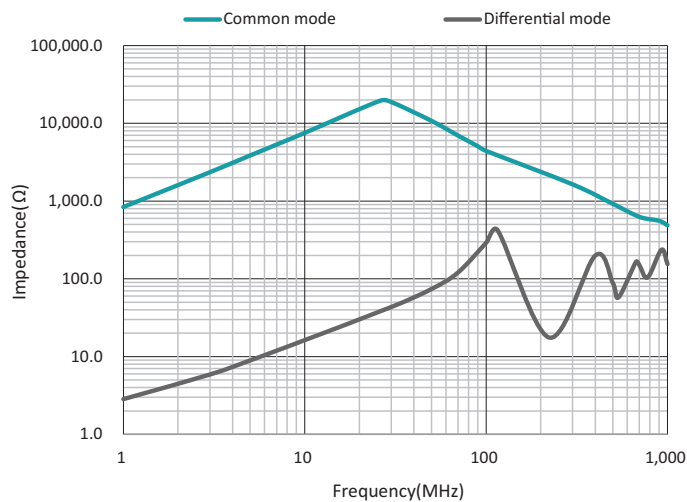
Impedance vs Frequency

Temp vs DC Current

PE-1812ACC510STS



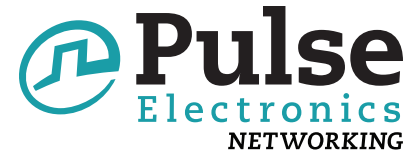
PE-1812ACC101STS



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Reliability Test

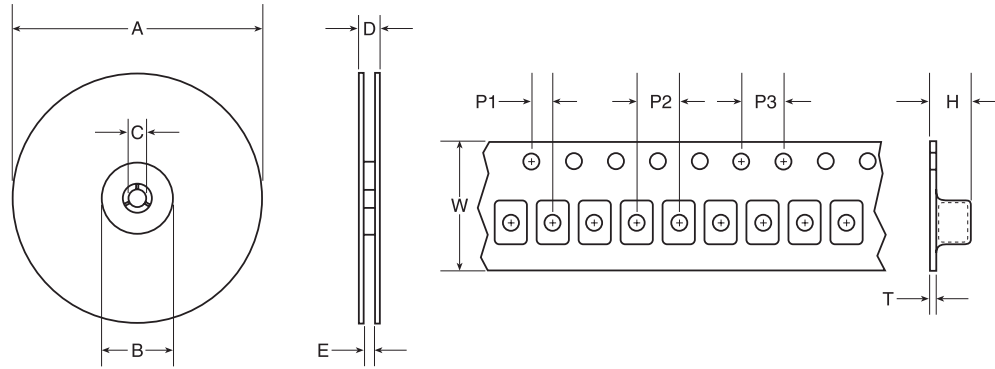
Item	Reference documents	Test Condition	Test Specification
1. High Temperature Exposure	MIL-STD-202 Method 108	1. Temperature: 125°C 2. Time: 1000 hours	1. No mechanical and electrical damage 2. Inductance shall not change more than $\pm 30\%$
2. Temperature Cycling	JESD22 Method JA-104	1. Temperature: 40°C~125°C 2. Number of cycles: 1000 cycle 3. Dwell time: 30 minutes	1. No mechanical and electrical damage 2. Inductance shall not change more than $\pm 30\%$
3. Biased Humidity Test	MIL-STD-202 Method 103	1. Temperature: 85 ± 5 °C 2. Time: 1000 hours 3. Humidity: 85 $\pm 5\%$ RH	1. No mechanical and electrical damage 2. Inductance shall not change more than $\pm 30\%$
4. Operational Life	MIL-PRF-27	1. Temperature: 125°C 2. Time: 1000 hours 3. Apply rated current	1. No mechanical and electrical damage 2. Inductance shall not change more than $\pm 30\%$
5. External Visual	MIL-STD-883 Method 2009	Inspect product construction, marking and workmanship	Per product specification standard
6. Physical Dimensions	JESD22 Method JB-100	Verify physical dimensions to the applicable product detail specification	Per product specification standard
7. Resistance to solvents	MIL-STD-202 Method 215	Immerse into solvent for 3 ± 0.5 minutes & brush 10 times for their cycles.	1. No body change in appearance 2. No marking blurred. 3. Inductance shall not change more than $\pm 30\%$
8. Vibration Test	MIL-STD-202 Method 204	1. Frequency and Amplified: 10-2000-10 Hz, 1.5mm 2. Direction: X, Y, Z 3. Test duration: 2 hours for each direction, 6 hours in total	1. No mechanical and electrical damage 2. Inductance shall not change more than $\pm 30\%$
9. Resistance to Soldering Heat Test	MIL-STD-202 Method 210	1. Temperature: 250 ± 5 °C 2. Time: (temp. ≥ 217 °C) 60~150 Second 3. IR reflow times: 3 times	1. No mechanical and electrical damage 2. Inductance shall not change more than $\pm 30\%$
10. Rated Current	MIL-STD-202 Method 330	Apply rated current for 5 seconds.	1. No mechanical and electrical damage 2. Inductance shall not change more than $\pm 30\%$
11. Temperature Rise	MIL-PRF-27	Apply rated current for 10 minutes.	1. No mechanical and electrical damage 2. Inductance shall not change more than $\pm 30\%$
12. Over load	MIL-PRF-27	Apply twice as rated current for 5 minutes.	1. No mechanical and electrical damage 2. Inductance shall not change more than $\pm 30\%$
13. Solderability Test	J-STD-002	1. Bakeing in pre-testing: 155 ± 5 °C / 16Hours ± 30 min. 2. Peak temperature: 240 ± 5 °C 3. Time: (temp. ≥ 217 °C) 60~150 Second 4. IR reflow times: 1 time	The terminal shall be at least 95% covered with fresh solder.
14. Electrical Characterization	User Spec.	1. Operating temperature: -40°C~125°C 2. Room Temperature: 25°C	1. No mechanical and electrical damage 2. Inductance shall not change more than $\pm 30\%$
15. Withstanding Voltage Test	MIL-STD-202 Method 201	1. DV: 500V 2. Time: 1 minute	1. During the test no breakdown. 2. The characteristic is normal after test.
16. Drop	JESD22-B111	Package & Drop down from 1m. In 1 angle 1 ridge & 2 surfaces orientation	1. No case deformation or change in appearance. 2. Inductance shall not change more than $\pm 30\%$
17. Terminal Strength Test	JIS-C-6429	1. Apply push force to samples mounted on PCB. 2. Force of 1.8 kg for 60 ± 1 seconds.	After test, inductors shall be on mechanical damage.

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Tape and Reel Specifications



Reel Dimensions (mm)							Tape Dimensions (mm)					
Series	Parts per Reel	A	B	C	D	E	W	P1	P2	P3	H	T
1210 ACC	2000	178	60	13.5	12	9	8	2	4	4	2.5	0.26
1812 ACC	500	178	60	13	17	14	12	2	8	4	4	0.35

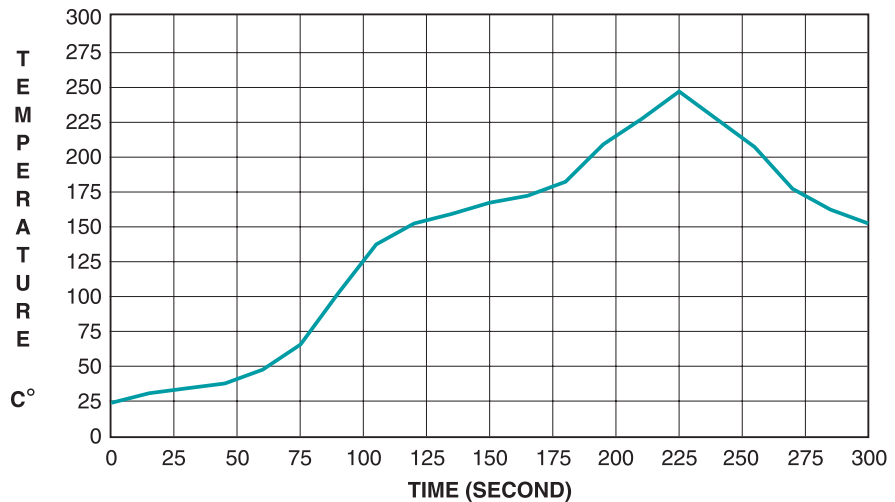
III. Description:

- Ferrite drum core construction
- Magnetically shielded
- Enameled copper wire: H class
- Product weight: 0.15g (ref.)
- Moisture sensitivity Level 1
- Products comply with RoHS' requirements
- Halogen Free available

IV. General specification:

- Storage temp: -40°C to +125°C
- Operating temp: -40°C to +125°C
(Temp. rise included)
- Resistance to solder heat: 250°C 10 secs.

Recommended Solder Heat Resistance Profile



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